



IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

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Type of Components

JIS C 5442:1996	Low power electromagnetic relays for industrial control circuits
IEC 61076-1:2006	Connectors for electronic equipment
IEC 60384-1:2016	Fixed capacitors for use in electronic equipment
IEC 60115-1:2008	Fixed resistors for use in electronic equipment

ENVIRONMENTAL TEST

IEC 60068-2-1:2007	Cold
IEC 60068-2-2:2007	Dry heat
IEC 60068-2-11:1981	Salt mist
IEC 60068-2-14:2009	Change of temperature
IEC 60068-2-30:2005	Damp heat, cyclic (12+12-hour cycle)
IEC 60068-2-38:2009	Composite temperature/humidity cyclic test
JIS C 60068-2-42:1993	Sulphur dioxide test for contacts and connections
JIS C 60068-2-43:1993	Hydrogen sulphide test for contacts and connections
JIS C 60068-2-52:2000	Salt mist, cyclic (sodium chloride solution)
IEC 60068-2-66:1994	Damp heat, steady state (unsaturated pressurized vapour)
IEC 60068-2-67:1995	Damp heat, steady state, accelerated test primarily intended for components
IEC 60068-2-78:2012	Damp heat, steady state

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